



US00D425438S

United States Patent [19] Chen

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[54] **CLAMP OHMMETER**

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[**] Term: **14 Years**

[21] Appl. No.: **29/107,117**

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[51] **LOC (7) Cl. 10-04**

[52] **U.S. Cl. D10/78**

[58] **Field of Search D10/79; 324/126,**
324/127; 336/175, 212; 338/32 R

[56] **References Cited**

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Primary Examiner—Antoine Duval Davis

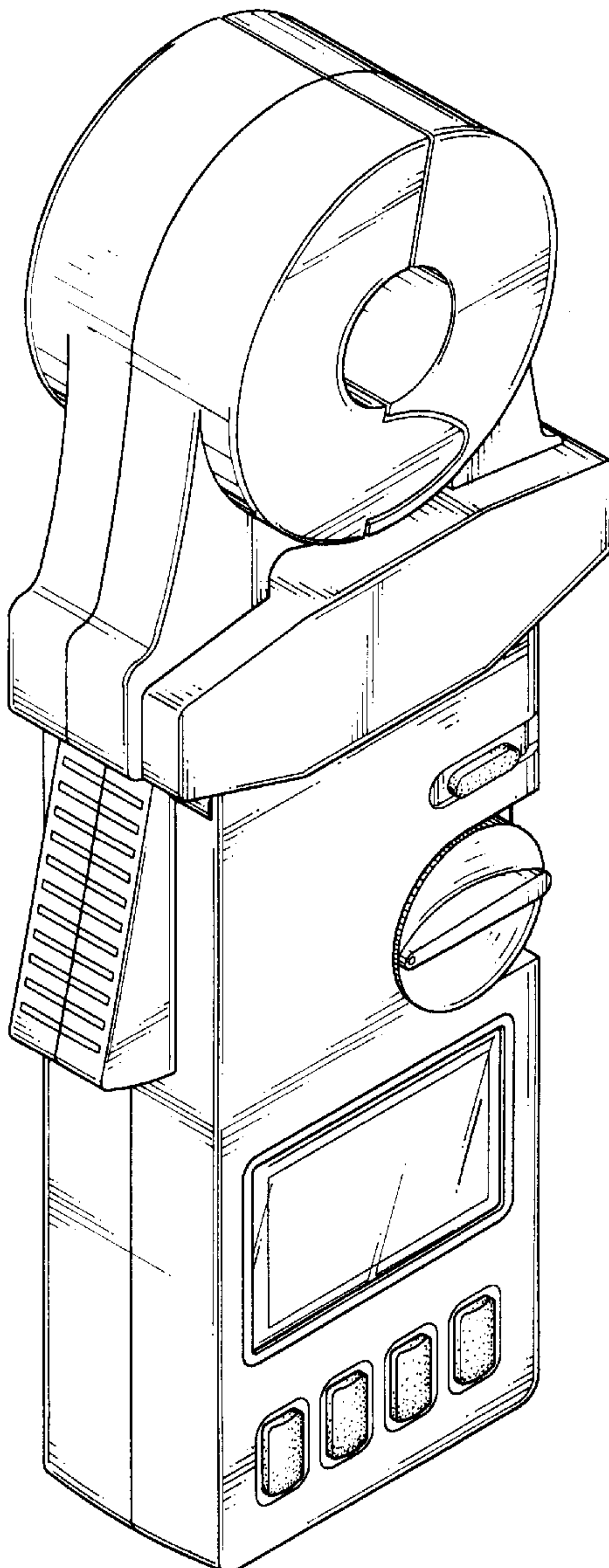
[57] **CLAIM**

The ornamental design for a clamp ohmmeter, as shown.

DESCRIPTION

FIG. 1 is a front-right-top perspective view of a clamp ohmmeter, showing my new design;
FIG. 2 is a front elevational view thereof;
FIG. 3 is a rear elevational view thereof;
FIG. 4 is a left elevational view thereof;
FIG. 5 is a right elevational view thereof;
FIG. 6 is top plan view thereof; and,
FIG. 7 is a bottom plan view thereof.

1 Claim, 4 Drawing Sheets



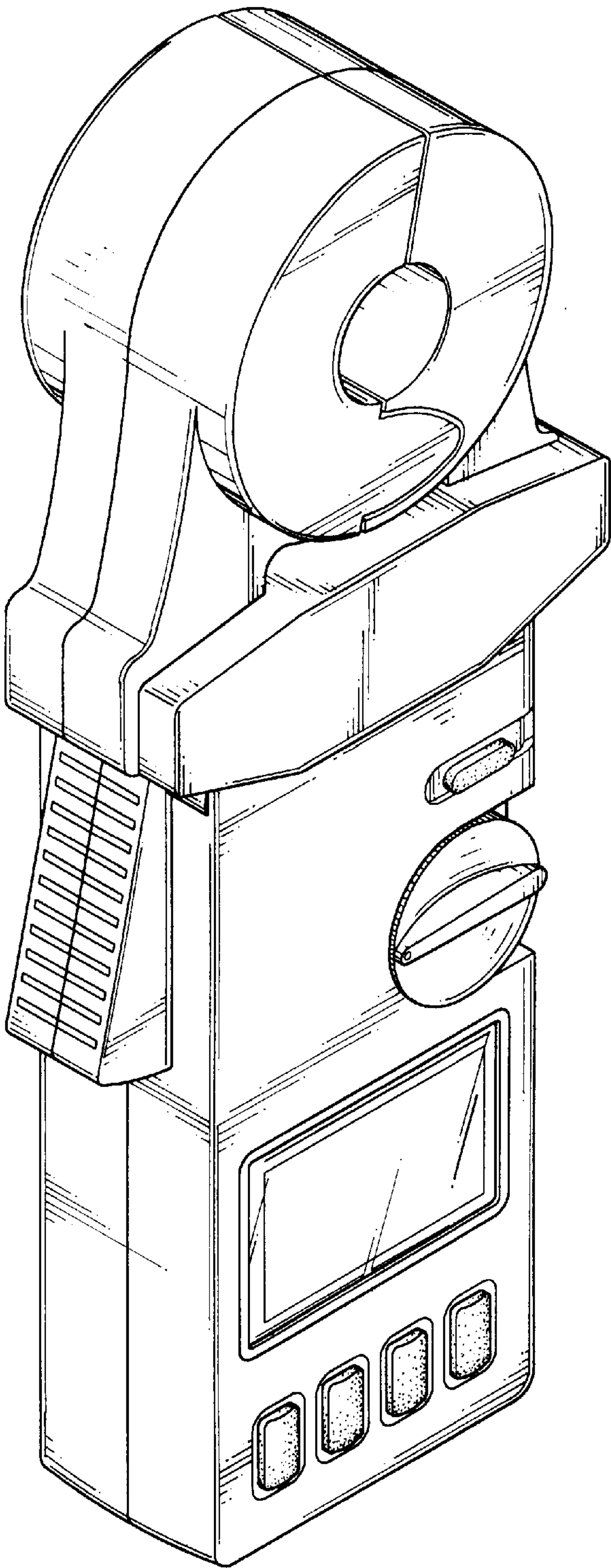


FIG.1

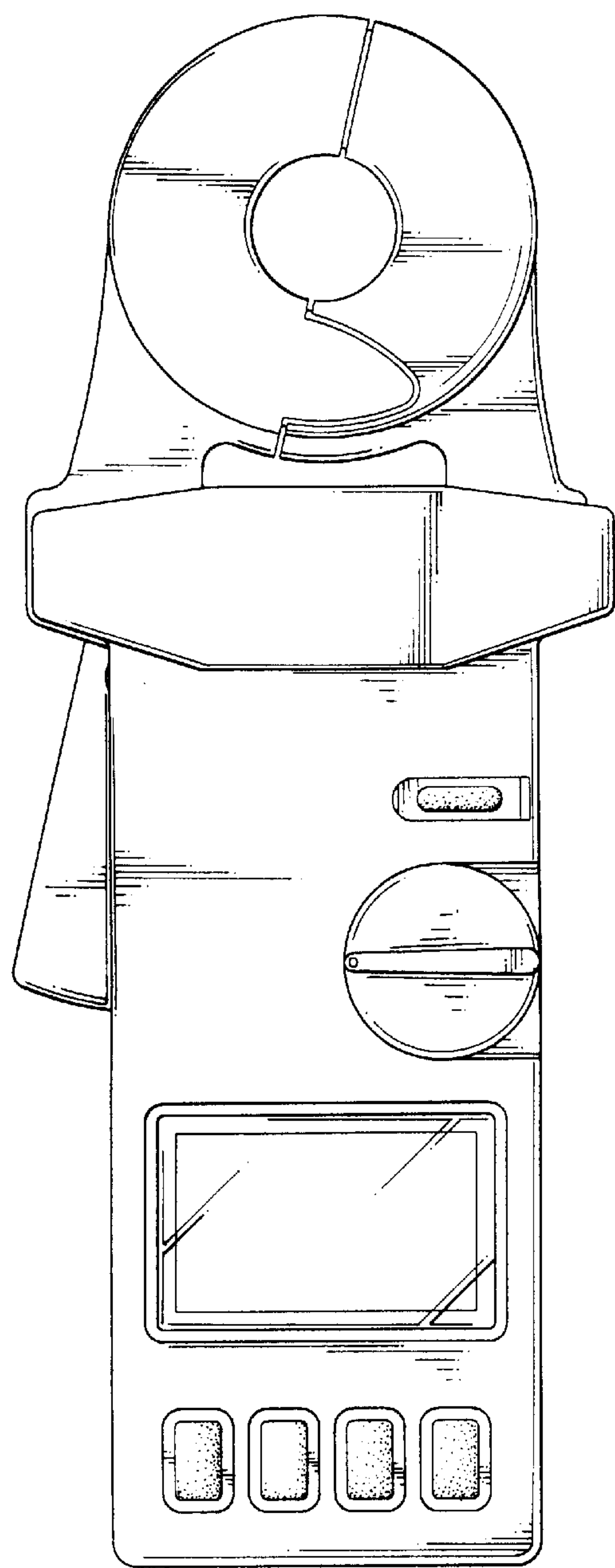


FIG. 2

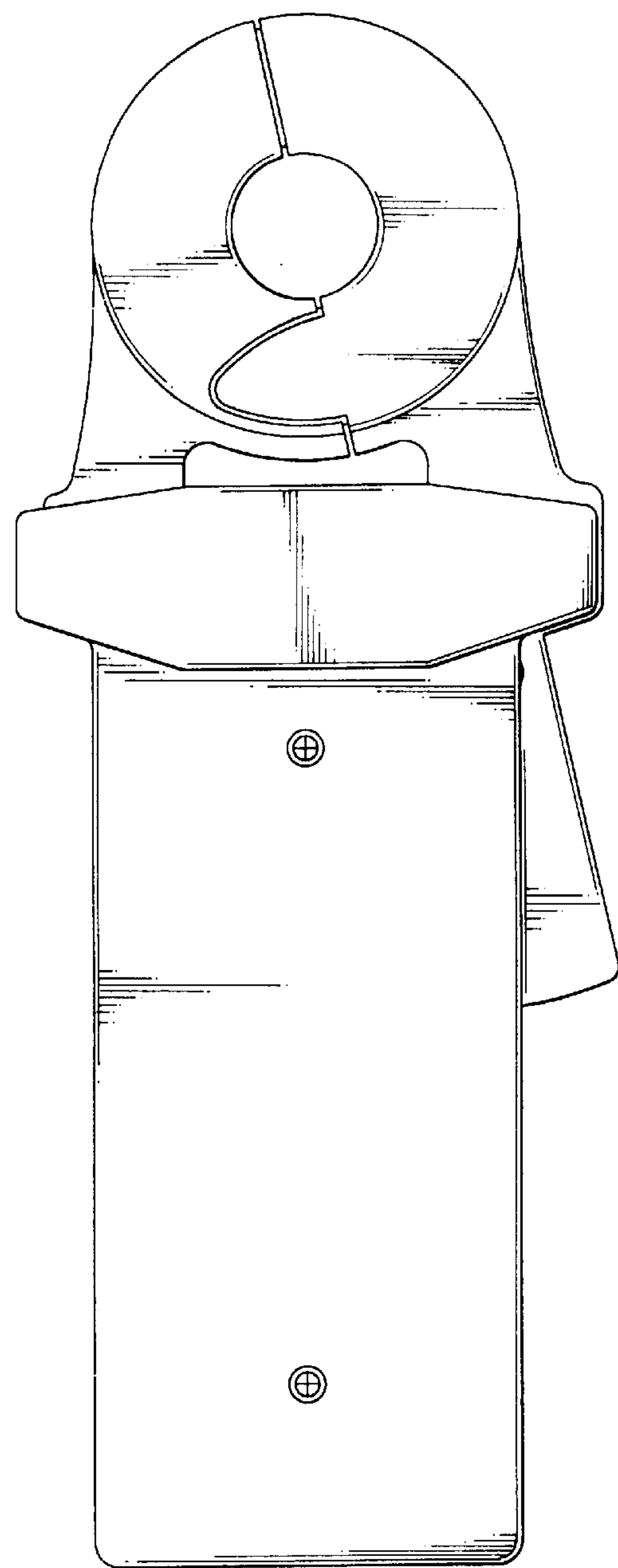


FIG. 3

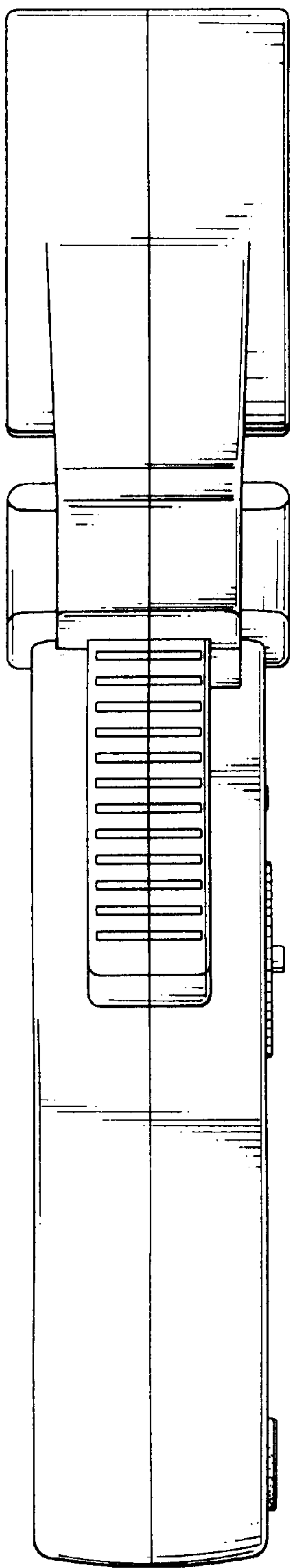


FIG. 4

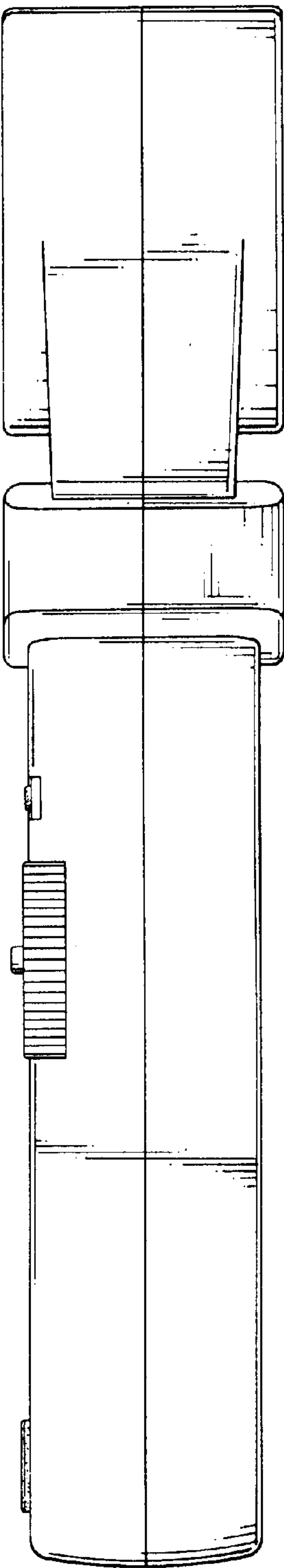


FIG. 5

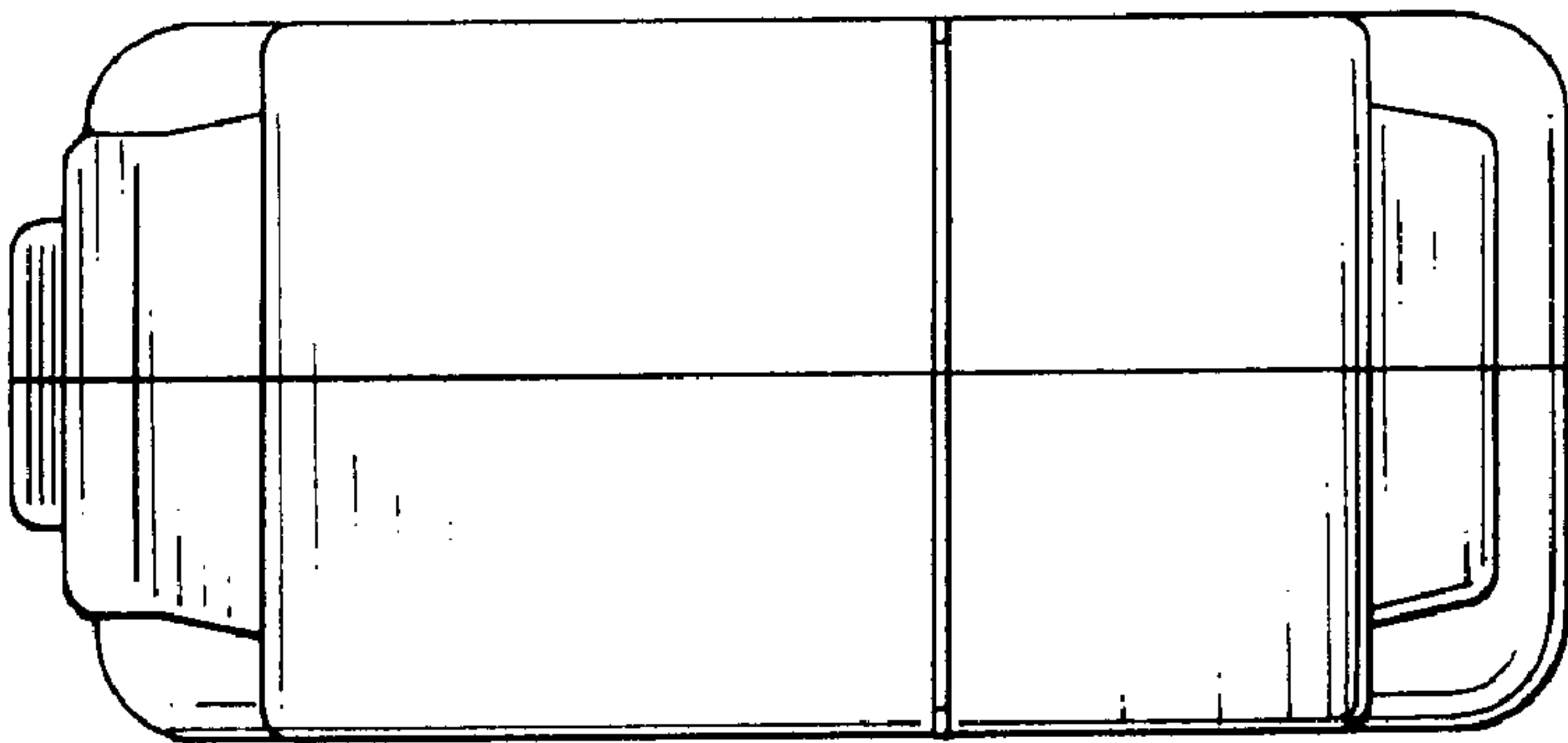


FIG. 6

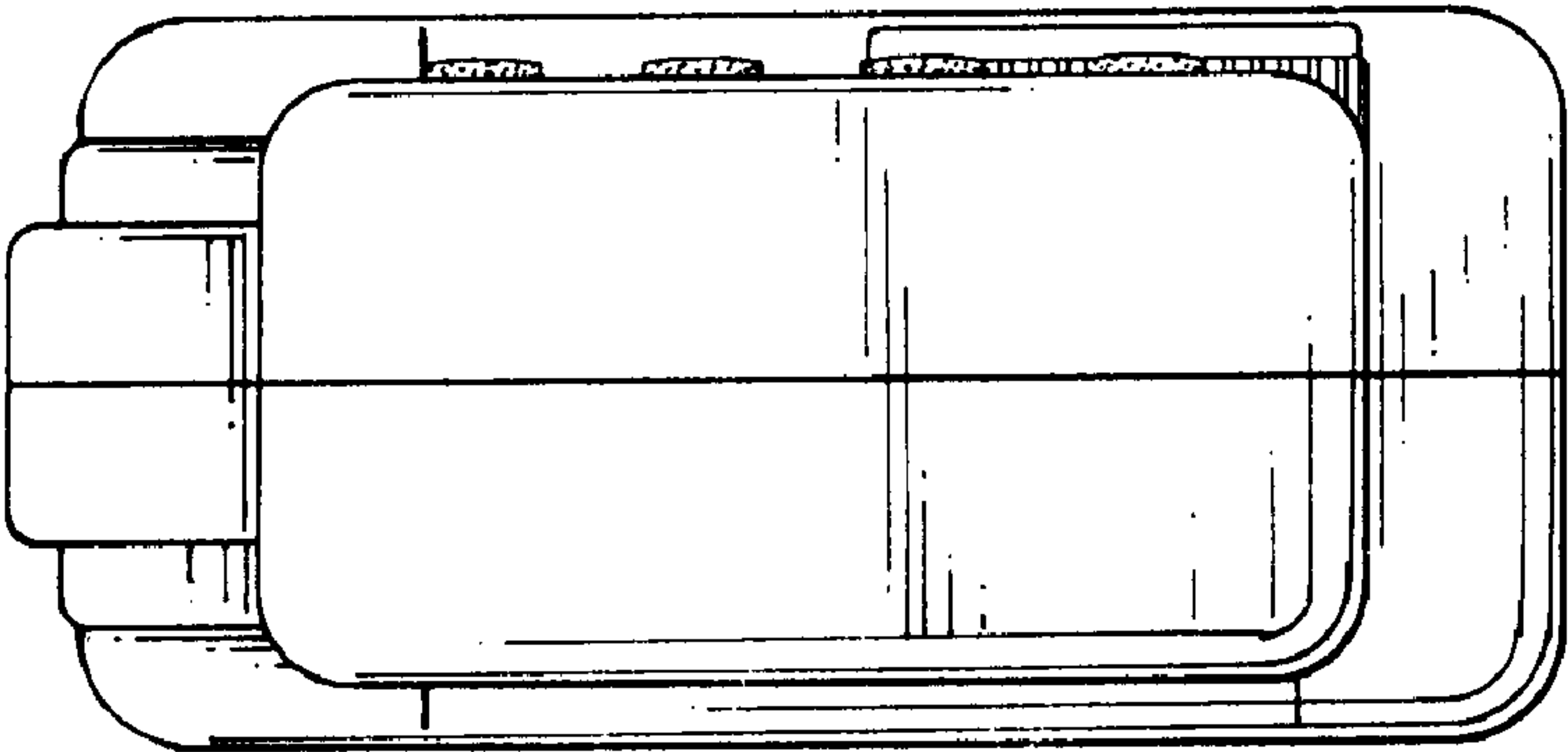


FIG. 7